

IRG4BC20SD-SPbF

INSULATED GATE BIPOLAR TRANSISTOR WITH ULTRAFAST SOFT RECOVERY DIODE

Standard Speed IGBT

Features

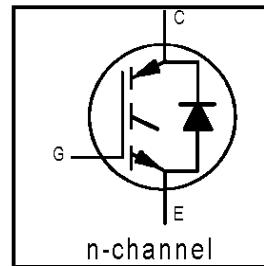
- Extremely low voltage drop 1.4Vtyp. @ 10A
- S-Series: Minimizes power dissipation at up to 3 KHz PWM frequency in inverter drives, up to 4 KHz in brushless DC drives.
- Very Tight Vce(on) distribution
- IGBT co-packaged with HEXFRED™ ultrafast, ultra-soft-recovery anti-parallel diodes for use in bridge configurations
- Industry standard D²Pak package
- Lead-Free

Benefits

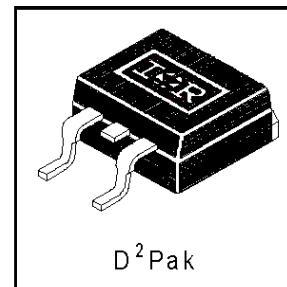
- Generation 4 IGBT's offer highest efficiencies available
- IGBT's optimized for specific application conditions
- HEXFRED diodes optimized for performance with IGBT's. Minimized recovery characteristics require less/no snubbing
- Lower losses than MOSFET's conduction and Diode losses

Absolute Maximum Ratings

	Parameter	Max.	Units
V _{CES}	Collector-to-Emitter Voltage	600	V
I _C @ T _C = 25°C	Continuous Collector Current	19	
I _C @ T _C = 100°C	Continuous Collector Current	10	
I _{CM}	Pulsed Collector Current ①	38	A
I _{LM}	Clamped Inductive Load Current ②	38	
I _F @ T _C = 100°C	Diode Continuous Forward Current	7.0	
I _{FM}	Diode Maximum Forward Current	38	
V _{GE}	Gate-to-Emitter Voltage	± 20	V
P _D @ T _C = 25°C	Maximum Power Dissipation	60	
P _D @ T _C = 100°C	Maximum Power Dissipation	24	W
T _J	Operating Junction and	-55 to +150	
T _{STG}	Storage Temperature Range		



V_{CES} = 600V
V_{CE(on)} typ. = 1.4V
@V_{GE} = 15V, I_C = 10A



Thermal Resistance

	Parameter	Typ.	Max.	Units
R _{qJC}	Junction-to-Case - IGBT	—	2.1	°C/W
R _{qJC}	Junction-to-Case - Diode	—	3.5	
R _{qJA}	Junction-to-Ambient (PCB Mounted, steady-state)*	—	80	
Wt	Weight	1.44	—	

* When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994.

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Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)CES}$	Collector-to-Emitter Breakdown Voltage f	600	—	—	V	$V_{GE} = 0V, I_C = 250\mu\text{A}$
$DV_{(BR)CES}/dT_J$	Temperature Coeff. of Breakdown Voltage	—	0.75	—	V/ $^\circ\text{C}$	$V_{GE} = 0V, I_C = 1.0\text{mA}$
$V_{CE(on)}$	Collector-to-Emitter Saturation Voltage	—	1.40	1.6	V	$I_C = 10\text{A}, V_{GE} = 15\text{V}$
		—	1.85	—		$I_C = 19\text{A}$
		—	1.44	—		$I_C = 10\text{A}, T_J = 150^\circ\text{C}$
$V_{GE(th)}$	Gate Threshold Voltage	3.0	—	6.0		$V_{CE} = V_{GE}, I_C = 250\mu\text{A}$
$DV_{GE(th)}/dT_J$	Temperature Coeff. of Threshold Voltage	—	-11	—	mV/ $^\circ\text{C}$	$V_{CE} = V_{GE}, I_C = 250\mu\text{A}$
g_{fe}	Forward Transconductance $\textcircled{4}$	2.0	5.8	—	S	$V_{CE} = 100\text{V}, I_C = 10\text{A}$
I_{CES}	Zero Gate Voltage Collector Current	—	—	250	μA	$V_{GE} = 0V, V_{CE} = 600\text{V}$
		—	—	1700		$V_{GE} = 0V, V_{CE} = 600\text{V}, T_J = 150^\circ\text{C}$
V_{FM}	Diode Forward Voltage Drop	—	1.4	1.7	V	$I_C = 8.0\text{A}$
		—	1.3	1.6		$I_C = 8.0\text{A}, T_J = 150^\circ\text{C}$
I_{GES}	Gate-to-Emitter Leakage Current	—	—	± 100	nA	$V_{GE} = \pm 20\text{V}$

Switching Characteristics @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions	
Q_g	Total Gate Charge (turn-on)	—	27	40	nC	$I_C = 10\text{A}$	
Q_{ge}	Gate - Emitter Charge (turn-on)	—	4.3	6.5		$V_{CC} = 400\text{V}$	
Q_{gc}	Gate - Collector Charge (turn-on)	—	10	15		$V_{GE} = 15\text{V}$	
$t_{d(on)}$	Turn-On Delay Time	—	62	—	ns	$T_J = 25^\circ\text{C}$	
t_r	Rise Time	—	32	—		$I_C = 10\text{A}, V_{CC} = 480\text{V}$	
$t_{d(off)}$	Turn-Off Delay Time	—	690	1040		$V_{GE} = 15\text{V}, R_G = 50\text{W}$	
t_f	Fall Time	—	480	730	mJ	Energy losses include "tail" and diode reverse recovery. See Fig. 9, 10, 11, 18	
E_{on}	Turn-On Switching Loss	—	0.32	—			
E_{off}	Turn-Off Switching Loss	—	2.58	—			
E_{ts}	Total Switching Loss	—	2.90	4.5	ns		
$t_{d(on)}$	Turn-On Delay Time	—	64	—		$T_J = 150^\circ\text{C}$, See Fig. 10, 11, 18	
t_r	Rise Time	—	35	—		$I_C = 10\text{A}, V_{CC} = 480\text{V}$	
$t_{d(off)}$	Turn-Off Delay Time	—	980	—		$V_{GE} = 15\text{V}, R_G = 50\text{W}$	
t_f	Fall Time	—	800	—		Energy losses include "tail" and diode reverse recovery.	
E_{ts}	Total Switching Loss	—	4.33	—	mJ		
L_E	Internal Emitter Inductance	—	7.5	—		Measured 5mm from package	
C_{ies}	Input Capacitance	—	550	—		pF	$V_{GE} = 0\text{V}$
C_{oes}	Output Capacitance	—	39	—			$V_{CC} = 30\text{V}$
C_{res}	Reverse Transfer Capacitance	—	7.1	—			$f = 1.0\text{MHz}$
t_{rr}	Diode Reverse Recovery Time	—	37	55	ns	$T_J = 25^\circ\text{C}$	
		—	55	90		$T_J = 125^\circ\text{C}$	
I_{rr}	Diode Peak Reverse Recovery Current	—	3.5	5.0	A	$T_J = 25^\circ\text{C}$	
		—	4.5	8.0		$T_J = 125^\circ\text{C}$	
Q_{rr}	Diode Reverse Recovery Charge	—	65	138	nC	$T_J = 25^\circ\text{C}$	
		—	124	360		$T_J = 125^\circ\text{C}$	
$di_{(rec)M}/dt$	Diode Peak Rate of Fall of Recovery During t_b	—	240	—	A/ μs	$T_J = 25^\circ\text{C}$	
		—	210	—		$T_J = 125^\circ\text{C}$	

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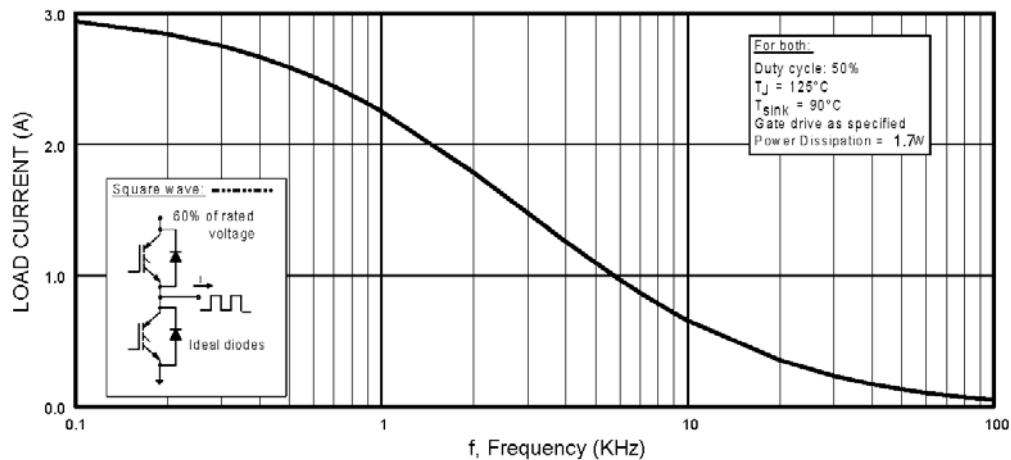


Fig. 1 - Typical Load Current vs. Frequency
 (Load Current = I_{RMS} of fundamental)

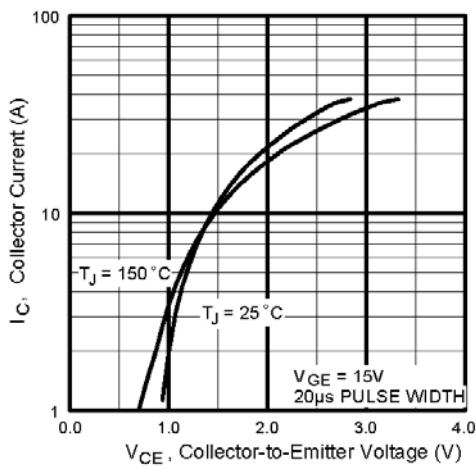


Fig. 2 - Typical Output Characteristics

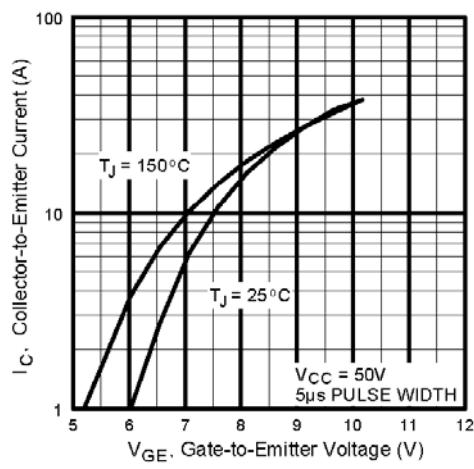


Fig. 3 - Typical Transfer Characteristics

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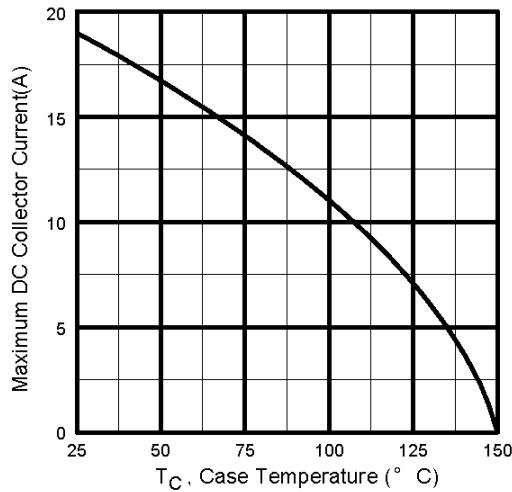


Fig. 4 - Maximum Collector Current vs. Case Temperature

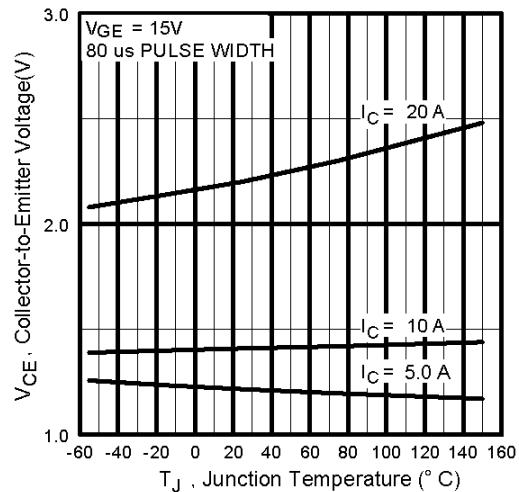


Fig. 5 - Typical Collector-to-Emitter Voltage vs. Junction Temperature

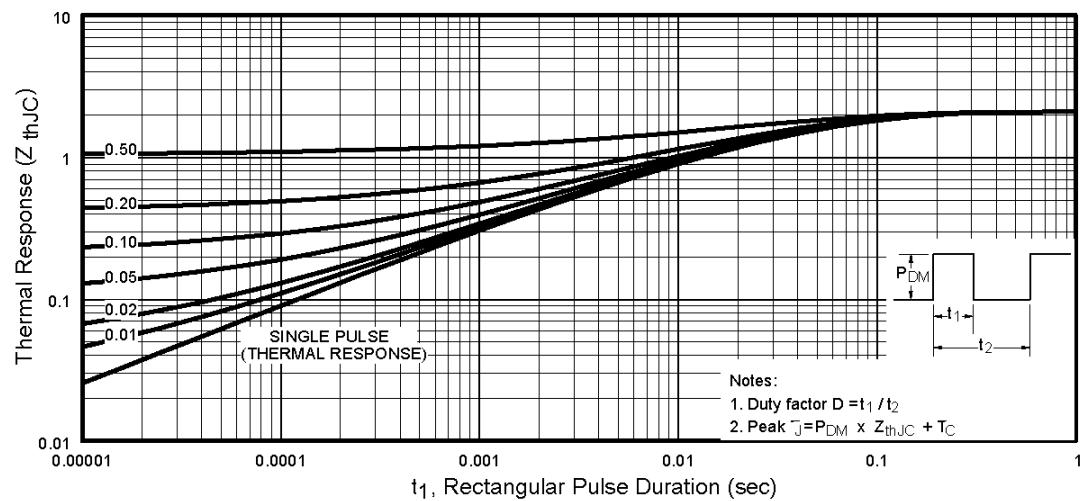


Fig. 6 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

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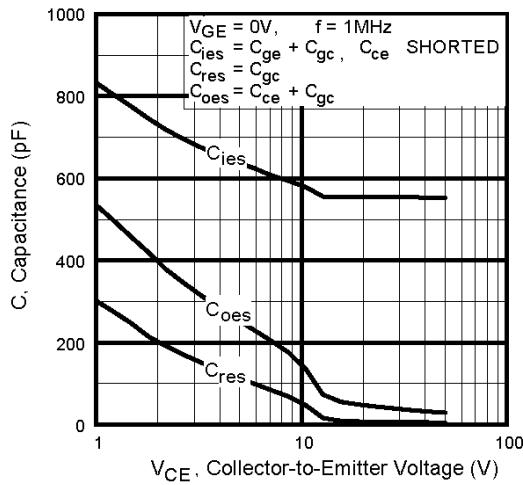


Fig. 7 - Typical Capacitance vs.
Collector-to-Emitter Voltage

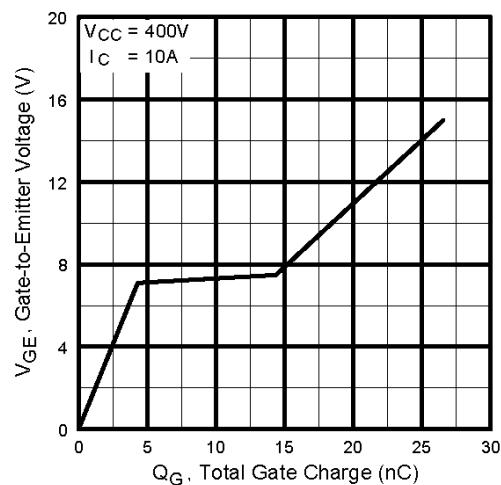


Fig. 8 - Typical Gate Charge vs.
Gate-to-Emitter Voltage

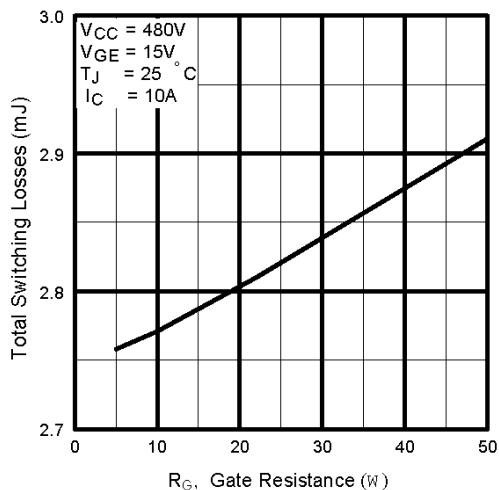


Fig. 9 - Typical Switching Losses vs. Gate
Resistance

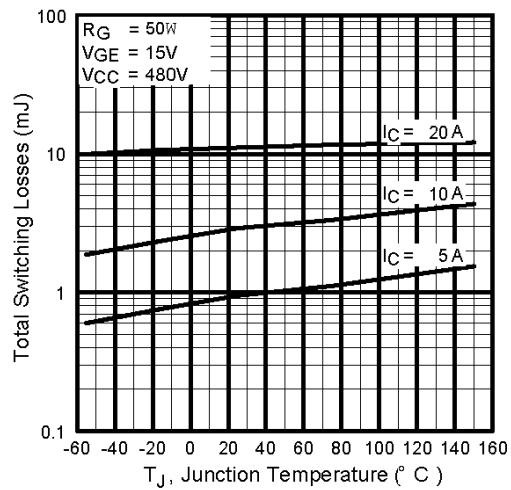


Fig. 10 - Typical Switching Losses vs.
Junction Temperature

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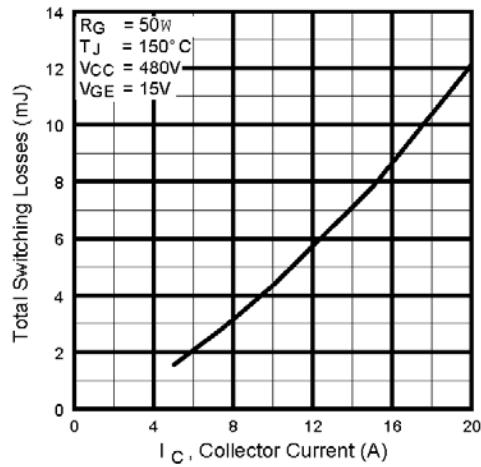


Fig. 11 - Typical Switching Losses vs.
Collector-to-Emitter Current

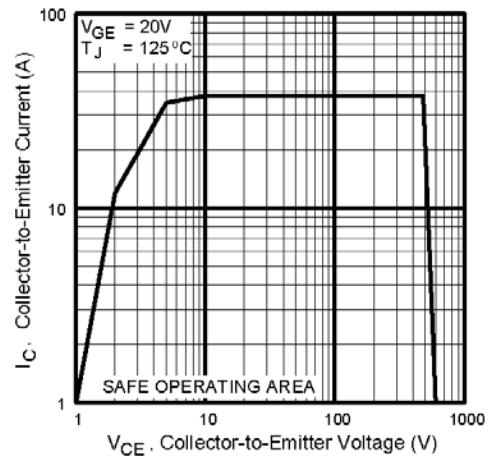


Fig. 12 - Turn-Off SOA

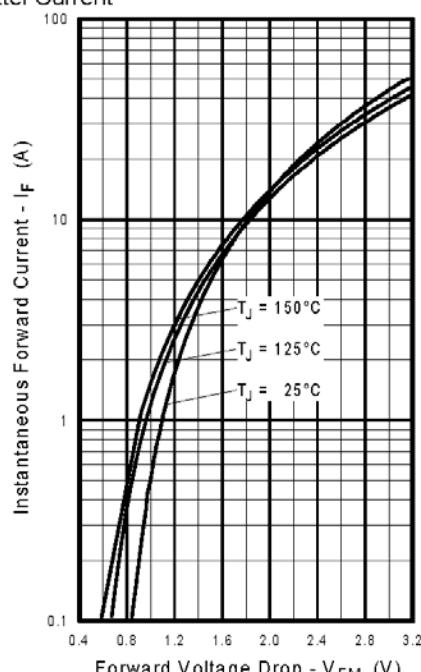


Fig. 13 - Maximum Forward Voltage Drop vs. Instantaneous Forward Current

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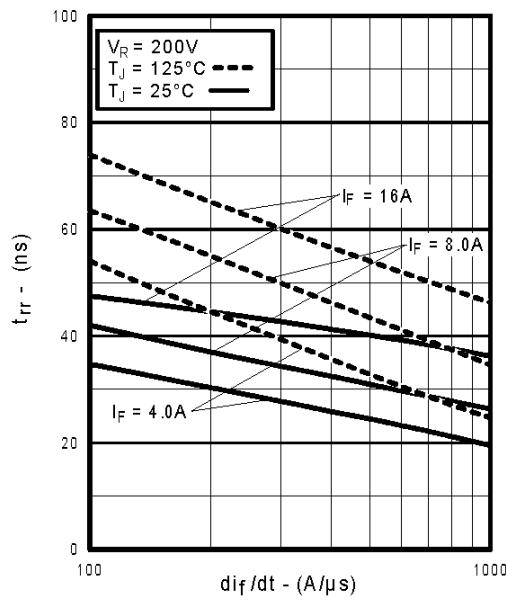


Fig. 14 - Typical Reverse Recovery vs. di_f/dt

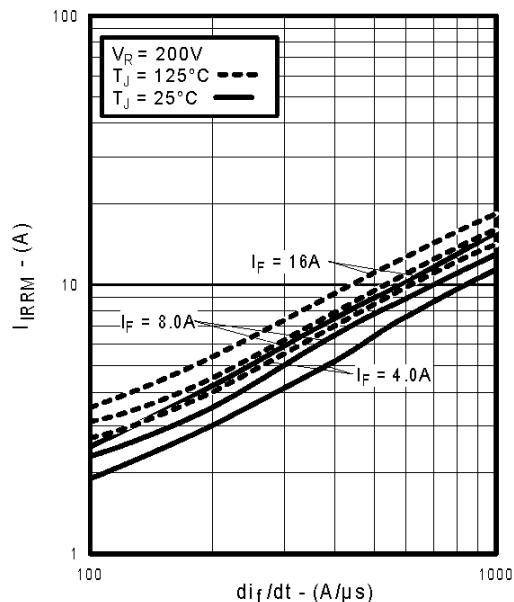


Fig. 15 - Typical Recovery Current vs. di_f/dt

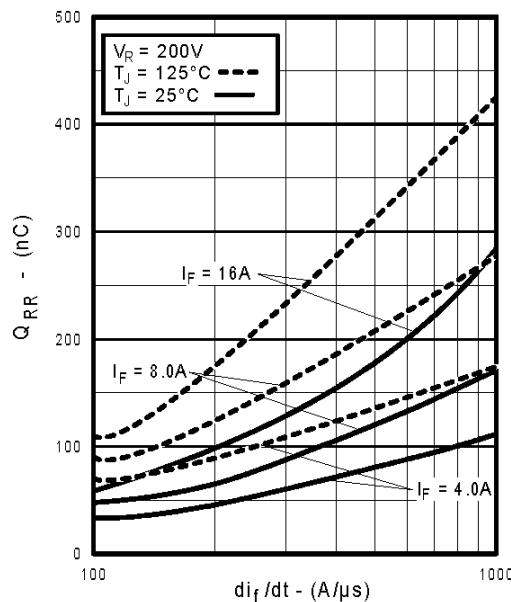


Fig. 16 - Typical Stored Charge vs. di_f/dt

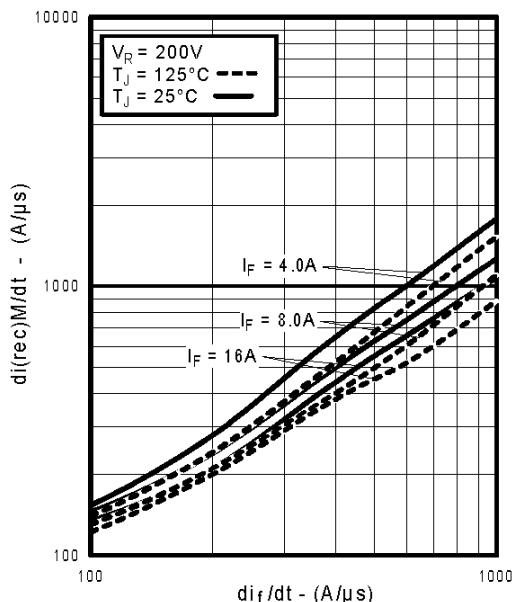


Fig. 17 - Typical $dI_{(rec)}/dt$ vs. di_f/dt

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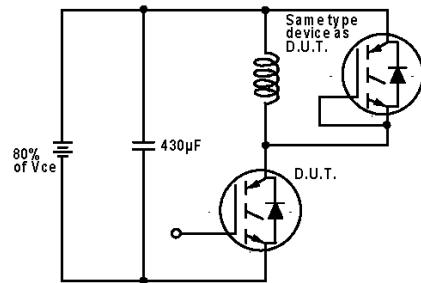


Fig. 18a - Test Circuit for Measurement of I_{LM} , E_{on} , $E_{off(diode)}$, t_{rr} , Q_{rr} , I_{rr} , $t_{d(on)}$, t_r , $t_{d(off)}$, t_f

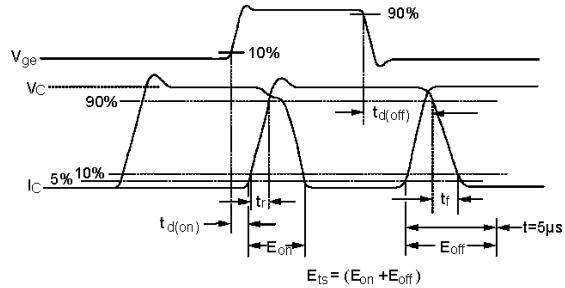


Fig. 18b - Test Waveforms for Circuit of Fig. 18a, Defining E_{off} , $t_{d(off)}$, t_f

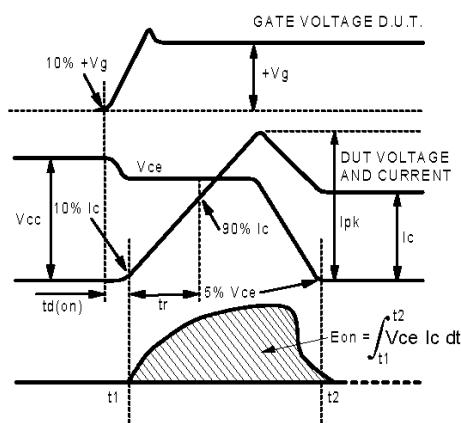


Fig. 18c - Test Waveforms for Circuit of Fig. 18a, Defining E_{on} , $t_{d(on)}$, t_r

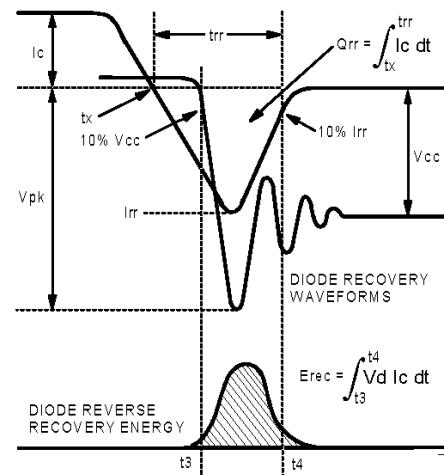


Fig. 18d - Test Waveforms for Circuit of Fig. 18a, Defining E_{rec} , t_{rr} , Q_{rr} , I_{rr}

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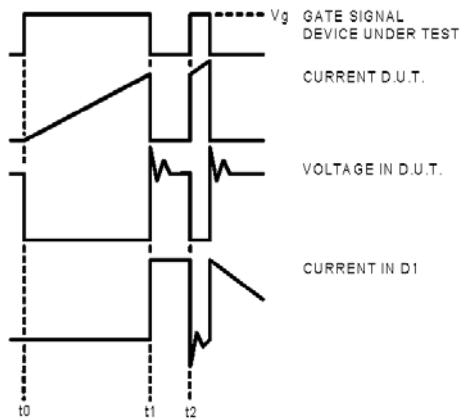


Figure 18e. Macro Waveforms for Figure 18a's Test Circuit

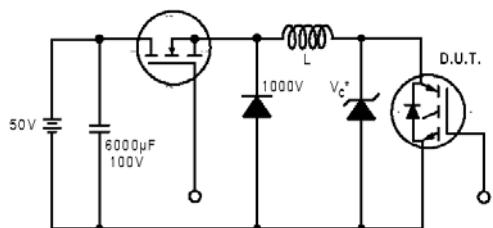


Figure 19. Clamped Inductive Load Test Circuit

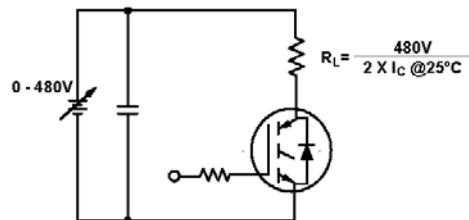


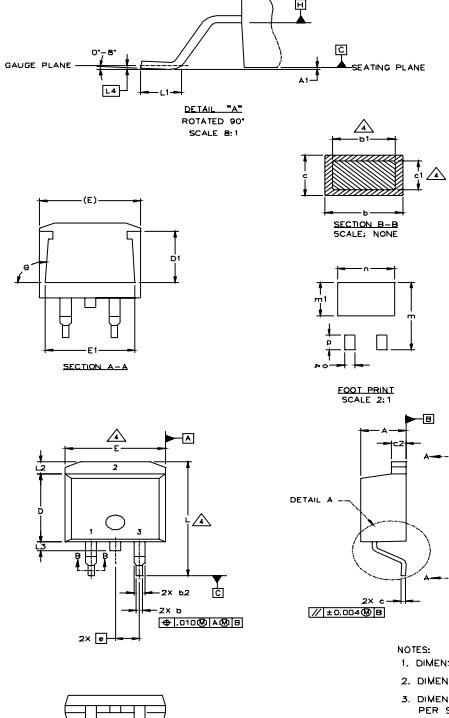
Figure 20. Pulsed Collector Current Test Circuit

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D²Pak Package Outline

Dimensions are shown in millimeters (inches)



SYMBOL	DIMENSIONS				NOTE	
	MILLIMETERS		INCHES			
	MIN.	MAX.	MIN.	MAX.		
A	4.06	4.83	.160	.190		
A1	0.51	0.127	.005			
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	4	
b2	1.14	1.40	.045	.055		
c	0.43	0.63	.017	.025		
c1	0.38	0.74	.015	.029	4	
c2	1.14	1.40	.045	.055		
D	8.51	9.65	.335	.380	3	
D1	5.33		.210			
E	9.65	10.67	.380	.420	3	
E1	6.22		.245			
e	2.54	BSC	.100	BSC		
L	14.61	15.88	.575	.625		
L1	1.78	2.79	.070	.110		
L2		1.65		.065		
L3	1.27	1.78	.050	.070		
L4	0.25	BSC	.010	BSC		
m	17.78		.700			
m1	8.89		.350			
n	11.43		.450			
o	2.08		.082			
p	3.81		.150			
θ	90°		90°			
		9.3°		9.3°		

LEAD ASSIGNMENTS

HEXFET	IGBTs...CoPACK	DIODES
1.- GATE 2.- DRAIN 3.- SOURCE	1.- GATE 2.- COLLECTOR 3.- Emitter	1.- ANODE + 2.- CATHODE 3.- ANODE

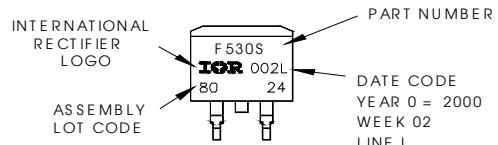
* PART DEPENDENT.

NOTES:
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES]
 3. DIMENSION D & E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.127 [0.05"]
 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.
 4. DIMENSION b1 AND c1 APPLY TO BASE METAL ONLY.
 5. CONTROLLING DIMENSION: INCH.

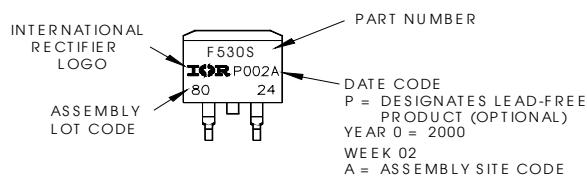
D²Pak Part Marking Information (Lead-Free)

EXAMPLE: THIS IS AN IRF530S WITH
LOT CODE 8024
ASSEMBLED ON WW 02, 2000
IN THE ASSEMBLY LINE "L"

Note: "P" in assembly line
position indicates "Lead-Free"



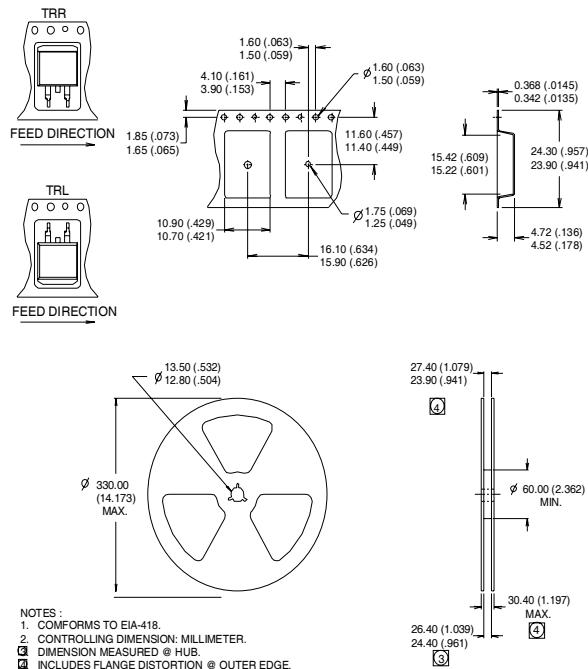
OR



Notes:

- ① Repetitive rating: $V_{GE}=20V$; pulse width limited by maximum junction temperature (figure 20)
- ② $V_{CC}=80\%$ (V_{CES}), $V_{GE}=20V$, $L=10\mu H$, $R_G = 50\Omega$ (figure 19)
- ③ Pulse width $\leq 80\mu s$; duty factor $\leq 0.1\%$.
- ④ Pulse width $5.0\mu s$, single shot.

D²Pak Tape & Reel Infomation



Data and specifications subject to change without notice.

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Note: For the most current drawings please refer to the IR website at:
<http://www.irf.com/package/>